Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/606,366	WEI ET AL.
Examiner	Art Unit
Jo Ann Rinaudo	1644

SEARCHED					
Class	Subclass	Date	Examiner		
	-				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	1				
L					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST and STN	2/23/2006	JR		
Inventors searched- Wei, MH. Yan, C. DiFrancesco, V. Beasley, E.	2/23/2006	JR		
Patent applications reviewed- 09/956,993 09/816,088	2/23/2006	JR		